

OptiMOSTM3 Power-Transistor

Features

- N-channel, normal level
- Excellent gate charge x R_{DS(on)} product (FOM)
- Very low on-resistance R_{DS(on)}
- 175 °C operating temperature
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC¹⁾ for target application
- Halogen-free according to IEC61249-2-21
- Ideal for high-frequency switching and synchronous rectification

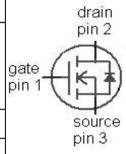
Product Summary

V _{DS}	250	V
$R_{\mathrm{DS(on),max}}$	20	mΩ
I _D	64	Α





Туре	IPB200N25N3 G	IPP200N25N3 G	IPI200N25N3 G
	1 2 (tab)	123	123
Package	PG-TO263-3	PG-TO220-3	PG-TO262-3
Marking	200N25N	200N25N	200N25N



Maximum ratings, at T_i =25 °C, unless otherwise specified

Parameter	Symbol	Conditions	Value	Unit
Continuous drain current	ID	T _C =25 °C	64	А
		T _C =100 °C	46	
Pulsed drain current ²⁾	I _{D,pulse}	T _C =25 °C	256	
Avalanche energy, single pulse	E _{AS}	I_{D} =47 A, R_{GS} =25 Ω	320	mJ
Reverse diode dv/dt	dv/dt		10	kV/μs
Gate source voltage	V_{GS}		±20	V
Power dissipation	P_{tot}	T _C =25 °C	300	W
Operating and storage temperature	$T_{\rm j},T_{\rm stg}$		-55 175	°C
IEC climatic category; DIN IEC 68-1			55/175/56	

¹⁾J-STD20 and JESD22

²⁾ See figure 3



Parameter

IPB200N25N3 G IPP200N25N3 G IPI200N25N3 G

min.

Values		Unit
typ.	max.	

Thermal characteristics

Thermal resistance, junction - case	R_{thJC}		-	-	0.5	K/W
Thermal resistance, junction -	R_{thJA}	minimal footprint	-	-	62	
ambient		6 cm2 cooling area ³⁾	-	-	40	

Symbol | Conditions

Electrical characteristics, at T_i =25 °C, unless otherwise specified

Static characteristics

Drain-source breakdown voltage	$V_{(BR)DSS}$	V _{GS} =0 V, I _D =1 mA	250	ı	-	V
Gate threshold voltage	$V_{\rm GS(th)}$	$V_{\rm DS} = V_{\rm GS}, I_{\rm D} = 270 \ \mu {\rm A}$	2	3	4	
Zero gate voltage drain current	I _{DSS}	$V_{\rm DS}$ =200 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =25 °C	1	0.1	1	μΑ
		$V_{\rm DS}$ =200 V, $V_{\rm GS}$ =0 V, $T_{\rm j}$ =125 °C	-	10	100	
Gate-source leakage current	I _{GSS}	V _{GS} =20 V, V _{DS} =0 V	-	1	100	nA
Drain-source on-state resistance	$R_{DS(on)}$	V _{GS} =10 V, I _D =64 A	ı	17.5	20	mΩ
Gate resistance	R_{G}		ı	2.4	-	Ω
Transconductance	g_{fs}	$ V_{\rm DS} > 2 I_{\rm D} R_{\rm DS(on)max},$ $I_{\rm D} = 64~{\rm A}$	61	122	-	S

 $^{^{3)}}$ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm 2 (one layer, 70 μ m thick) copper area for drain connection. PCB is vertical in still air.



Parameter	Symbol	Conditions		Values		Unit
			min.	typ.	max.	
Dynamic characteristics						
Input capacitance	Ciss		-	5340	7100	pF
Output capacitance	Coss	V _{GS} =0 V, V _{DS} =100 V, f=1 MHz	-	297	395	
Reverse transfer capacitance	C _{rss}		-	4	-	
Turn-on delay time	t _{d(on)}		-	18	-	ns
Rise time	t _r	V _{DD} =100 V, V _{GS} =10 V, I _D =25 A,	-	20	-	
Turn-off delay time	$t_{d(off)}$	$R_{\rm G}$ =1.6 Ω	-	45	-	
Fall time	t_{f}		-	12	-	
Gate Charge Characteristics ⁴⁾				-		
Gate to source charge	Q _{gs}		-	22	-	nC
Gate to drain charge	Q_{gd}],, ,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	-	7	-	
Switching charge	Q _{sw}	$V_{\rm DD}$ =100 V, $I_{\rm D}$ =25 A, $V_{\rm GS}$ =0 to 10 V	-	13	-	
Gate charge total	Qg		-	64	86	
Gate plateau voltage	V _{plateau}		-	4.2	-	V
Output charge	Q _{oss}	V _{DD} =100 V, V _{GS} =0 V	-	135	179	nC
Reverse Diode						
Diode continous forward current	Is	T -25 °C	-	-	64	А
Diode pulse current	I _{S,pulse}	- T _C =25 °C	-	-	256	
Diode forward voltage	V_{SD}	V _{GS} =0 V, I _F =64 A, T _j =25 °C	-	1	1.2	V
Reverse recovery time	t _{rr}	V _R =100 V, I _F =25 A,	-	170	-	ns
Reverse recovery charge	Q _{rr}	di _F /dt=100 A/µs	-	780	-	nC

⁴⁾ See figure 16 for gate charge parameter definition



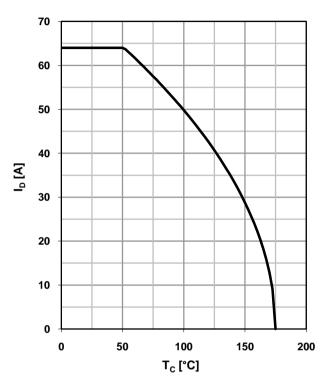
1 Power dissipation

$P_{\text{tot}} = f(T_{\text{C}})$

320 280 240 200 P_{tot} [W] 160 120 80 40 0 100 0 50 150 200 T_C [°C]

2 Drain current

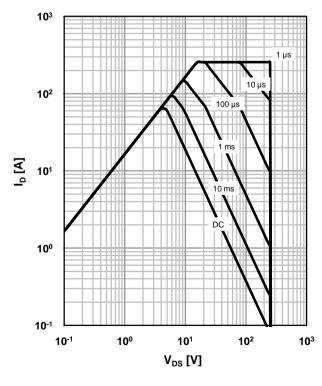
$$I_D=f(T_C); V_{GS} \ge 10 \text{ V}$$



3 Safe operating area

 $I_D=f(V_{DS}); T_C=25 \text{ °C}; D=0$

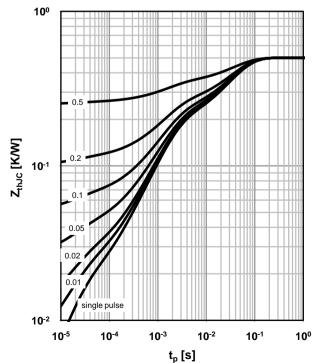
parameter: t_p



4 Max. transient thermal impedance

 Z_{thJC} =f(t_{p})

parameter: $D=t_p/T$

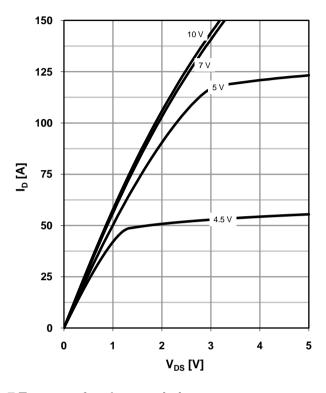




5 Typ. output characteristics

 $I_D=f(V_{DS}); T_j=25 °C$

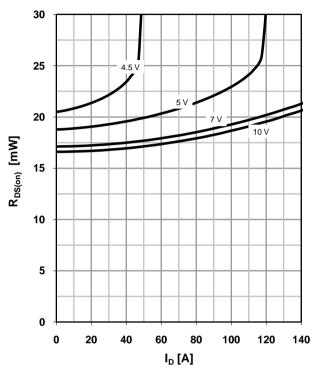
parameter: V_{GS}



6 Typ. drain-source on resistance

 $R_{DS(on)}=f(I_D); T_i=25 °C$

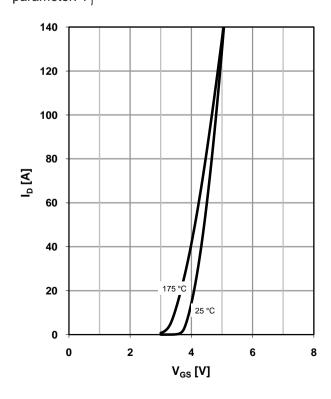
parameter: V_{GS}



7 Typ. transfer characteristics

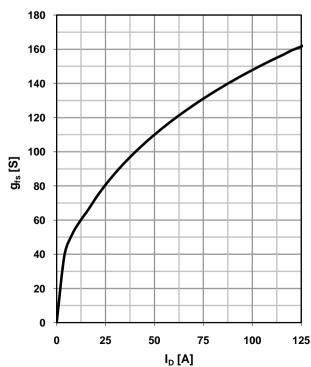
 $I_{D}=f(V_{GS}); |V_{DS}|>2|I_{D}|R_{DS(on)max}$

parameter: T_i



8 Typ. forward transconductance

 g_{fs} =f(I_D); T_j =25 °C





9 Drain-source on-state resistance

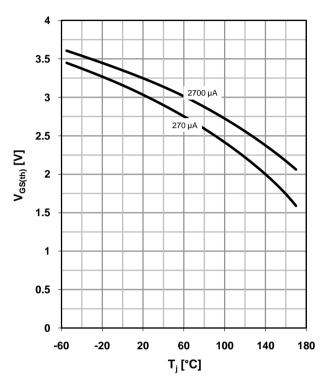
 $R_{DS(on)} = f(T_i); I_D = 64 \text{ A}; V_{GS} = 10 \text{ V}$

70 60 50 40 30 20 10 0 -60 -20 20 60 100 140 180 T_i [°C]

10 Typ. gate threshold voltage

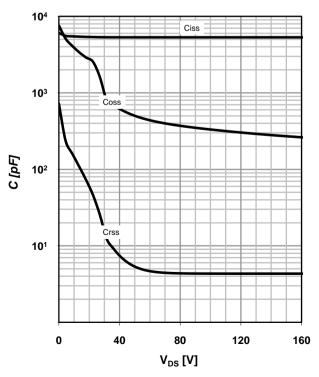
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: I_D



11 Typ. capacitances

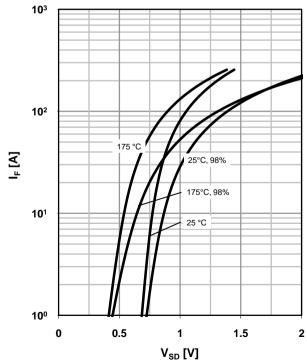
 $C=f(V_{DS}); V_{GS}=0 V; f=1 MHz$



12 Forward characteristics of reverse diode

 $I_{\mathsf{F}} = \mathsf{f}(V_{\mathsf{SD}})$

parameter: T_i

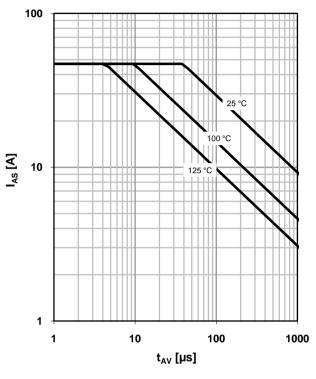




13 Avalanche characteristics

 $I_{AS}=f(t_{AV}); R_{GS}=25 \Omega$

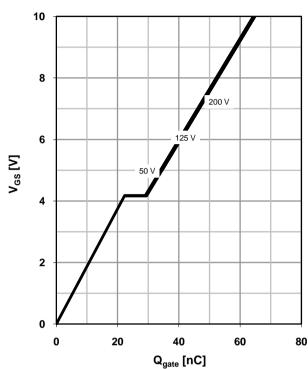
parameter: $T_{j(start)}$



14 Typ. gate charge

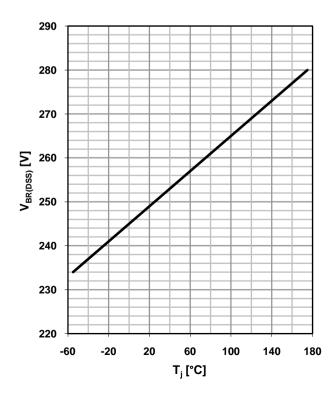
 V_{GS} =f(Q_{gate}); I_D =25 A pulsed

parameter: $V_{\rm DD}$

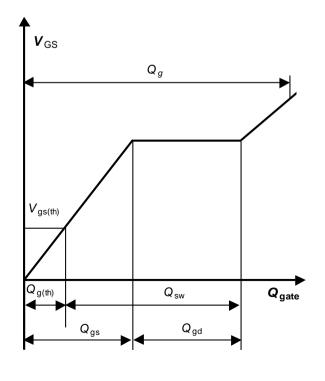


15 Drain-source breakdown voltage

 $V_{BR(DSS)}=f(T_j); I_D=1 \text{ mA}$

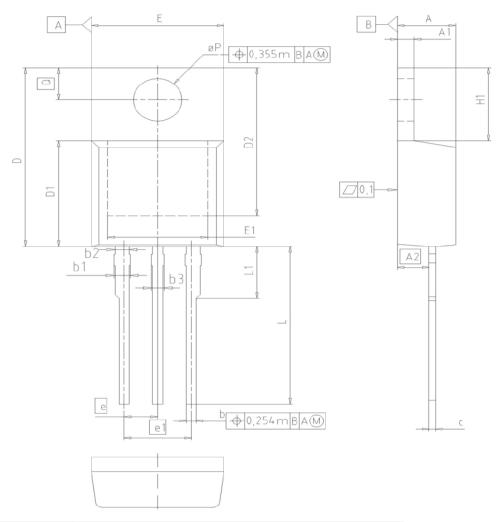


16 Gate charge waveforms

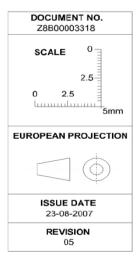




PG-TO220-3: Outline

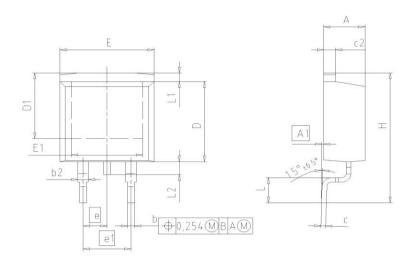


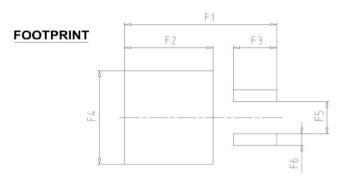
DIM	MILLI	METERS	INC	HES	
DIM	MIN	MAX	MIN	MAX	
Α	4.30	4.57	0.169	0.180	
A1	1.17	1.40	0.046	0.055	
A2	2.15	2.72	0.085	0.107	
b	0.65	0.86	0.026	0.034	
b 1	0.95	1.40	0.037	0.055	
b2	0.95	1.15	0.037	0.045	
b3	0.65	1.15	0.026	0.045	
С	0.33	0.60	0.013	0.024	
D	14.81	15.95	0.583	0.628	
D1	8.51	9.45	0.335	0.372	
D2	12.19	13.10	0.480	0.516	
E	9.70	10.36	0.382	0.408	
E1	6.50	8.60	0.256	0.339	
е	2	.54	0.1	100	
e1	5	.08	0.2	200	
N		3	3		
H1	5.90	6.90	0.232	0.272	
L	13.00	14.00	0.512	0.551	
L1	-	4.80	-	0.189	
øΡ	3.60	3.89	0.142	0.153	
Q	2.60	3.00	0.102	0.118	



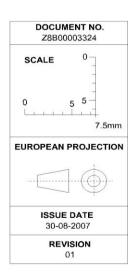


PG-TO263-3: Outline



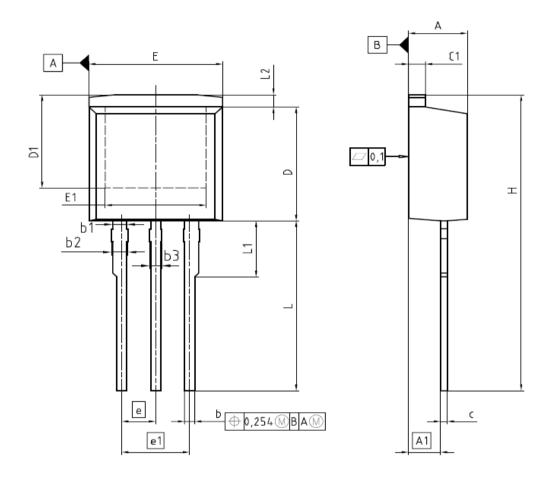


DIM	MILLIN	IETERS	INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.30	4.57	0.169	0.180
A1	0.00	0.25	0.000	0.010
b	0.65	0.85	0.026	0.033
b2	0.95	1.15	0.037	0.045
С	0.33	0.65	0.013	0.026
c2	1.17	1.40	0.046	0.055
D	8.51	9.45	0.335	0.372
D1	7.10	7.90	0.280	0.311
E	9.80	10.31	0.386	0.406
E1	6.50	8.60	0.256	0.339
е	2.54		0.100	
e1	5.08		0.200	
N		2		2
Н	14.61	15.88	0.575	0.625
L	2.29	3.00	0.090	0.118
L1	0.70	1.60	0.028	0.063
L2	1.00	1.78	0.039	0.070
F1	16.05	16.25	0.632	0.640
F2	9.30	9.50	0.366	0.374
F3	4.50	4.70	0.177	0.185
F4	10.70	10.90	0.421	0.429
F5	3.65	3.85	0.144	0.152
F6	1.25	1.45	0.049	0.057





PG-TO262-3: Outline



DIM	MILLIMI	ETERS	INCH	łES
DIM	MIN	MAX	MIN	MAX
Α	4.300	4.572	0.169	0.180
A1	2,150	2.718	0.085	0.107
b	0.650	0.864	0.026	0.034
Ь1	0.950	1.093	0.037	0.043
b2	0.950	1.400	0.037	0.055
ь3	0.650	1.118	0.026	0.044
С	0,330	0,600	0,013	0.024
c1	1.170	1.400	0.046	0.055
D	8,509	9.450	0.335	0.372
D1	6.900	-	0.272	-
E	9.700	10.363	0.382	0.408
E1	6,500	8,600	0,256	0.339
е	2.5	540 0.100		100
e1	5.0	5,080 0,200		200
N	3		;	3
L	13.000	14.000	0.512	0.551
L1	-	4.800	-	0.189
L2	-	1.727	-	0.068

REFERENCE Z8B00003325
SCALE 0
2.5- 0 2.5 1 5mm
EUROPEAN PROJECTION
ISSUE DATE 05-05-2006
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